

Revision 0.0 Customer Acceptance May 08
Specification

DF39079LIDFZV

Customer Specification



H8/36079 Series Part Number System

H8/36079 Series

Oct-08

Device	Type	Operating Temperature	Operating Voltage/ Maximum Clock Rate	POR	LVD	Package	Product Name	Renesas Order Code
H8/36079(128K/6K)	F-ZTAT (128K/6K)	Regular	Vcc=4.0 to 5.5V f=20MHz	Yes	Yes	FP-64A	HD64F36079GHV	DF36079GHV
						FP-64K	HD64F36079GFZV	DF36079GFZV
		I version				FP-64A	HD64F36079GHWV	DF36079GHWV
						FP-64K	HD64F36079GFZWV	DF36079GFZWV
		S version	Vcc=4.0 to 5.5V f=16MHz		No	FP-64A	HD64F36079GHSWV	DF36079GHSWV
						FP-64K	HD64F36079GFZSWV	DF36079GFZSWV
		Regular	Vcc=3.0 to 3.6V f=16MHz	Yes	Yes	FP-64A	HD64F36079LHV	DF36079LHV
						FP-64K	HD64F36079LFZV	DF36079LFZV
		I version				FP-64A	HD64F36079LHWV	DF36079LHWV
						FP-64K	HD64F36079LFZWV	DF36079LFZWV
		S version	Vcc=4.0 to 5.5V f=16MHz		No	FP-64A	HD64F36079LHSWV	DF36079LHSWV
						FP-64K	HD64F36079LFZSWV	DF36079LFZSWV
H8/36078(96K/6K)	F-ZTAT (96K/6K)	Regular	Vcc=4.0 to 5.5V f=20MHz	Yes	Yes	FP-64A	HD64F36078GHV	DF36078GHV
						FP-64K	HD64F36078GFZV	DF36078GFZV
		I version				FP-64A	HD64F36078GHWV	DF36078GHWV
						FP-64K	HD64F36078GFZWV	DF36078GFZWV
		S version	Vcc=4.0 to 5.5V f=16MHz		No	FP-64A	HD64F36078GHSWV	DF36078GHSWV
						FP-64K	HD64F36078GFZSWV	DF36078GFZSWV
		Regular	Vcc=3.0 to 3.6V f=16MHz	Yes	Yes	FP-64A	HD64F36078LHV	DF36078LHV
						FP-64K	HD64F36078LFZV	DF36078LFZV
		I version				FP-64A	HD64F36078LHWV	DF36078LHWV
						FP-64K	HD64F36078LFZWV	DF36078LFZWV
		S version	Vcc=4.0 to 5.5V f=16MHz		No	FP-64A	HD64F36078LHSWV	DF36078LHSWV
						FP-64K	HD64F36078LFZSWV	DF36078LFZSWV
H8/36077(56K/4K)	F-ZTAT (56K/54K)	Regular	Vcc=4.0 to 5.5V f=20MHz	Yes	Yes	FP-64A	HD64F36077GHV	HD64F36077GHV
						FP-64K	HD64F36077GFZV	HD64F36077GFZV
		I version				FP-64A	HD64F36077GHWV	DF36077GHWV
						FP-64K	HD64F36077GFZWV	DF36077GFZWV
		S version	Vcc=4.0 to 5.5V f=16MHz		No	FP-64A	HD64F36077GHSWV	DF36077GHSWV
						FP-64K	HD64F36077GFZSWV	DF36077GFZSWV
		Regular	Vcc=3.0 to 3.6V f=16MHz	Yes	Yes	FP-64A	HD64F36077LHV	DF36077LHV
						FP-64K	HD64F36077LFZV	DF36077LFZV
		I version				FP-64A	HD64F36077LHWV	DF36077LHWV
						FP-64K	HD64F36077LFZWV	DF36077LFZWV
		S version	Vcc=4.0 to 5.5V f=16MHz		No	FP-64A	HD64F36077LHSWV	DF36077LHSWV
						FP-64K	HD64F36077LFZSWV	DF36077LFZSWV
H8/36074(32K/4K)	F-ZTAT (32K/4K)	Regular	Vcc=4.0 to 5.5V f=20MHz	Yes	Yes	FP-64A	HD64F36074GHV	DF36074GHV
						FP-64K	HD64F36074GFZV	DF36074GFZV
		I version				FP-64A	HD64F36074GHWV	DF36074GHWV
						FP-64K	HD64F36074GFZWV	DF36074GFZWV
		S version	Vcc=4.0 to 5.5V f=16MHz		No	FP-64A	HD64F36074GHSWV	DF36074GHSWV
						FP-64K	HD64F36074GFZSWV	DF36074GFZSWV
		Regular	Vcc=3.0 to 3.6V f=16MHz	Yes	Yes	FP-64A	HD64F36074LHV	DF36074LHV
						FP-64K	HD64F36074LFZV	DF36074LFZV
		I version				FP-64A	HD64F36074LHWV	DF36074LHWV
						FP-64K	HD64F36074LFZWV	DF36074LFZWV
		S version	Vcc=4.0 to 5.5V f=16MHz		No	FP-64A	HD64F36074LHSWV	DF36074LHSWV
						FP-64K	HD64F36074LFZSWV	DF36074LFZSWV
H8/39079(128K/6K)	F-ZTAT (128K / 6K)	Regular	Vcc=3.0 to 3.6V f=16MHz	Yes	Yes	FP-64K	HD64F39079LIDFZV	DF39079LIDFZV (Indesit Custom Version)

The H8/300H Tiny Series Product Names are generally constructed according to the rules shown below. There are a limited number of exceptions to these rules.

HD64**F****36****A****B****C****D****E****F****V**

Leadfree
No code: Pb
V: Pb free

Memory Type

F : F-ZTAT

3: Mask

N: EEPROM + F-ZTAT

8: EEPROM + Mask

Group

6,7,8,9,.01, 02, 03, 04,
05,06, 07, 08, 09, 10

Two types 1 or 2 digits

eg HD64F3664H

eg HD64F36064FP

Memory Capacity

9: 128k/96k

8: 80k/96k

7: 56k/64k

6: 48k

5: 40k

4: 32k

3: 24k

2: 16k/8k

1: 12k/4k

0: 8k/2k

Mask ROM Code

3 digit customer

ROM code only for
MASKversion

Eg HD6433664A31H

G code

No code:

without

option

G: LVD &
POR

Package

F: FP-100

H: FP-80A

H: FP-64A

FP: FP-64E

FZ: FP-64K

FX: FP-48F

FY: FP-48B

FT: TNP-48

BP: DP-32S

FH :FP-32A

TP: FP-32D

P: DP-32S

Temperature & Quality

No code: -20 -> + 75° degrees

(standard)

I/W/D : -40 -> + 85° degrees

(standard)

SW : -20 -> + 105° degrees

(standard)

J: -40 -> + 85° degrees

(High Quality)

JE: -40 -> + 105° degrees

(High Quality)

K: -40 -> + 125° degrees

(High Quality)

The H8/300H Tiny Series Custom part Number for Indesit

Low Voltage

DF3907 9L ID FZ V Leadfree
No code: Pb
V: Pb free

Memory Type

F : F-ZTAT

3: Mask

N: EEPROM + F-ZTAT

8: EEPROM + Mask

9 - Custom Chip

Indesit

Temperature & Quality

No code: -20 -> + 75° degrees

(standard)

I/W/D : -40 -> + 85° degrees

(standard)

SW : -20 -> + 105° degrees

(standard)

J: -40 -> + 85° degrees

(High Quality)

JE: -40 -> + 105° degrees

(High Quality)

K: -40 -> + 125° degrees

(High Quality)

Group

6,7,8,9,01, 02, 03, 04,
05,06, 07, 08, 09, 10

Two types 1 or 2 digits

eg HD64F3664H

eg HD64F36064FP

Memory Capacity

9: 128k/96k

8: 80k/96k

7: 56k/64k

6: 48k

5: 40k

4: 32k

3: 24k

2: 16k/8k

1: 12k/4k

0: 8k/2k

Package

F: FP-100

H: FP-80A

H: FP-64A

FP: FP-64E

FZ: FP-64K

FX: FP-48F

FY: FP-48B

FT: TNP-48

BP: DP-32S

FH :FP-32A

TP: FP-32D

P: DP-32S

1. Absolute Maximum Ratings**Table 1.1 Absolute Maximum Ratings**

Item	Symbol	Value	Unit	Note
Power supply voltage	V_{CC}	−0.3 to +7.0	V	*1
Analog power supply voltage	AV_{CC}	−0.3 to +7.0	V	
Input voltage	Ports other than ports B and X1	V_{IN}	−0.3 to $V_{CC} + 0.3$	V
	Port B		−0.3 to $AV_{CC} + 0.3$	V
	X1		−0.3 to 4.3	V
Operating temperature	T_{opr}	−20 to +75	°C	
Storage temperature	T_{stg}	−55 to +125	°C	

Note: 1. Permanent damage may result if maximum ratings are exceeded. Normal operation should be under the conditions specified in Electrical Characteristics. Exceeding these values can result in incorrect operation and reduced reliability.

2. Electrical Characteristics

2.1 DC Characteristics

Table 2.1.1 DC Characteristics (1)

$V_{CC} = 3.0$ to 3.6 V, $V_{SS} = 0.0$ V, $T_a = -20$ to $+75^\circ\text{C}$, unless otherwise indicated.

Item	Symbol	Applicable Pins	Test Condition	Values			Unit	Notes
				Min.	Typ.	Max.		
Input high voltage	V_{IH}	RES, NMI, WKP0 to WKP5, IRQ0 to IRQ3, ADTRG, TMIB1, TMRIV, TMCIV, FTIOA0 to FTIOD0, FTIOA1 to FTIOD1, SCK3, SCK3_2, TRGV		$V_{CC} \times 0.9$	—	$V_{CC} + 0.3$	V	
		RXD, RXD_2, SCL, SDA, P10 to P12, P14 to P17, P20 to P24, P30 to P37, P50 to P57, P60 to P67, P70 to P72, P74 to P76, P85 to P87, PC0, PC1		$V_{CC} \times 0.8$	—	$V_{CC} + 0.3$	V	
		PB0 to PB7	$AV_{CC} = 3.0$ to 3.6 V	$AV_{CC} \times 0.8$	—	$AV_{CC} + 0.3$	V	
		OSC1		$V_{CC} - 0.3$	—	$V_{CC} + 0.3$	V	
Input low voltage	V_{IL}	RES, NMI, WKP0 to WKP5, IRQ0 to IRQ3, ADTRG, TMIB1, TMRIV, TMCIV, FTIOA0 to FTIOD0, FTIOA1 to FTIOD1, SCK3, SCK3_2, TRGV		-0.3	—	$V_{CC} \times 0.1$	V	

Note: Connect the TEST pin to Vss.

■ Electrical Characteristics

Item	Symbol	Applicable Pins	Test Condition	Values			Unit	Notes
				Min.	Typ.	Max.		
Input low voltage	V_{IL}	RXD, RXD_2, SCL, SDA, P10 to P12, P14 to P17, P20 to P24, P30 to P37, P50 to P57, P60 to P67, P70 to P72, P74 to P76, P85 to P87, PC0, PC1		-0.3	—	$V_{CC} \times 0.2$	V	
		PB0 to PB7	$AV_{CC} = 3.0$ to 3.6 V	-0.3	—	$AV_{CC} \times 0.2$	V	
		OSC1		-0.3	—	0.3	V	
Output high voltage	V_{OH}	P10 to P12, P14 to P17, P20 to P24, P30 to P37, P50 to P55, P60 to P67, P70 to P72, P74 to P76, P85 to P87, PC0, PC1	$-I_{OH} = 1.5$ mA	$V_{CC} - 1.0$	—	—	V	
			$-I_{OH} = 0.1$ mA	$V_{CC} - 0.5$	—	—		
		P56, P57	$-I_{OH} = 0.1$ mA	$V_{CC} - 2.0$	—	—	V	
Output low voltage	V_{OL}	P10 to P12, P14 to P17, P20 to P24, P30 to P37, P50 to P57, P70 to P72, P74 to P76, P85 to P87, PC0, PC1	$I_{OL} = 1.6$ mA	—	—	0.6	V	
			$I_{OL} = 0.4$ mA	—	—	0.4		
		P60 to P67	$I_{OL} = 20.0$ mA	—	—	1.5	V	
			$I_{OL} = 10.0$ mA	—	—	1.0		
			$I_{OL} = 1.6$ mA	—	—	0.4		
			$I_{OL} = 0.4$ mA	—	—	0.4		
		SCL, SDA	$I_{OL} = 6.0$ mA	—	—	0.6		
			$I_{OL} = 3.0$ mA	—	—	0.4		

■ Electrical Characteristics

Item	Symbol	Applicable Pins	Test Condition	Values			Unit	Notes
				Min	Typ	Max		
Input/output leakage current	I _{IL}	OSC1, TMIB1, RES, NMI, WKP0 to WKP5, IRQ0 to IRQ3, ADTRG, TRGV, TMRIV, TMCIV, FTIOA0 to FTIOD0, FTIOA1 to FTIOD1 RXD, SCK3, RXD_2, SCK3_2, SCL, SDA	V _{IN} = 0.5 V to (V _{CC} – 0.5 V)	—	—	1.0	μA	
		P10 to P12, P14 to P17, P20 to P24, P30 to P37, P50 to P57, P60 to P67, P70 to P72, P74 to P76, P85 to P87, PC0, PC1	V _{IN} = 0.5 V to (V _{CC} – 0.5 V)	—	—	1.0	μA	
		PB0 to PB7	V _{IN} = 0.5 V to (AV _{CC} – 0.5 V)	—	—	1.0	μA	
Pull-up MOS current	–I _p	P10 to P12, P14 to P17, P50 to P55	V _{CC} = 3.3 V, V _{IN} = 0.0 V	—	60.0	—	μA	
Input capacitance	C _{in}	All input pins except power supply pins	f = 4 MHz, V _{IN} = 0.0 V, T _a = 25°C	—	—	15.0	pF	
Active mode current consumption	I _{OP1}	V _{CC}	Active mode 1 V _{CC} = 3.3 V, f _{OSC} = 16 MHz	—	15.0	22.0	mA	*
			Active mode 1 V _{CC} = 3.3 V, f _{OSC} = 10 MHz	—	11.0	—		* Reference value
	I _{OP2}	V _{CC}	Active mode 2 V _{CC} = 3.3 V, f _{OSC} = 16 MHz	—	2.8	4.0	mA	*
			Active mode 2 V _{CC} = 3.3 V, f _{OSC} = 10 MHz	—	2.5	—		* Reference value

■ Electrical Characteristics

Item	Symbol	Applicable Pins	Test Condition	Values			Unit	Notes
				Min.	Typ.	Max.		
Sleep mode supply current	I _{SLEEP1}	V _{CC}	Sleep mode 1 V _{CC} = 3.3 V, f _{OSC} = 16 MHz	—	9.0	14.0	mA	*
			Sleep mode 1 V _{CC} = 3.3 V, f _{OSC} = 10 MHz	—	6.5	—		* Reference value
	I _{SLEEP2}	V _{CC}	Sleep mode 2 V _{CC} = 3.3 V, f _{OSC} = 16 MHz	—	2.2	3.5	mA	*
			Sleep mode 2 V _{CC} = 3.3 V, f _{OSC} = 10 MHz	—	2.0	—		* Reference value
Subactive mode supply current	I _{SUB}	V _{CC}	V _{CC} = 3.3 V 32-kHz crystal resonator ($\phi_{SUB} = \phi_W/2$)	—	95.0	145.0	μ A	*
			V _{CC} = 3.3 V 32-kHz crystal resonator ($\phi_{SUB} = \phi_W/8$)	—	85.0	—		* Reference value
Subsleep mode supply current	I _{SUBSP}	V _{CC}	V _{CC} = 3.3 V 32-kHz crystal resonator ($\phi_{SUB} = \phi_W/2$)	—	85.0	140.0	μ A	*
Standby mode supply current	I _{STBY}	V _{CC}	32-kHz crystal resonator not used	—	—	135.0	μ A	*
RAM data retention voltage	V _{RAM}	V _{CC}		2.0	—	—	V	

■ Electrical Characteristics

Note: * Pin states during supply current measurement are given below (excluding current in the pull-up MOS transistors and output buffers).

Mode	$\overline{RES}$ Pin	Internal State	Other Pins	Oscillator Pins
Active mode 1	V_{CC}	Operates	V_{CC}	Main clock: ceramic or crystal resonator, and on-chip oscillator
Active mode 2		Operates ($\phi_{OSC}/64$)		Subclock: Pin X1 = V_{SS}
Sleep mode 1	V_{CC}	Only timers operate	V_{CC}	
Sleep mode 2		Only timers operate ($\phi_{OSC}/64$)		
Subactive mode	V_{CC}	Operates	V_{CC}	Main clock: ceramic or crystal resonator, and on-chip oscillator
Subsleep mode	V_{CC}	Only timers operate	V_{CC}	Subclock: crystal resonator
Standby mode	V_{CC}	CPU and timers both stop	V_{CC}	Main clock: ceramic or crystal resonator, and on-chip oscillator Subclock: Pin X1 = V_{SS}

Table 2.2.2 DC Characteristics (2)

$V_{CC} = 3.0$ to 3.6 V, $V_{SS} = 0.0$ V, $T_a = -20$ to $+75^\circ\text{C}$, unless otherwise indicated.

Item	Symbol	Applicable Pins	Test Condition	Values			Unit
				Min.	Typ.	Max.	
Permissible output low current (per pin)	I_{OL}	Output pins except port 6, SCL, and SDA		—	—	2.0	mA
		Port 6		—	—	20.0	
Permissible output low current (total)	ΣI_{OL}	Output pins except port 6, SCL, and SDA		—	—	40.0	mA
		Port 6, SCL, and SDA		—	—	80.0	
Permissible output high current (per pin)	$ -I_{OH} $	All output pins		—	—	5.0	mA
Permissible output high current (total)	$ -\Sigma I_{OH} $	All output pins		—	—	50.0	mA

2.2 AC Characteristics

Table 2.2.1 AC Characteristics

$V_{CC} = 3.0$ to 3.6 V, $V_{SS} = 0.0$ V, $T_a = -20$ to $+75^{\circ}\text{C}$, unless otherwise indicated.

Item	Symbol	Applicable Pins	Test Condition	Values			Unit	Reference Figure
				Min.	Typ.	Max.		
System clock oscillation frequency	f_{OSC}	OSC1, OSC2		4.0	—	16.0	MHz	* ¹
System clock (ϕ) cycle time	t_{cyc}			1	—	64	t_{osc}	* ²
				—	—	12.8	μs	
Subclock oscillation frequency	f_W	X1, X2		—	32.768	—	kHz	
Watch clock (ϕ_W) cycle time	t_W	X1, X2		—	30.5	—	μs	
Subclock (ϕ_{SUB}) cycle time	t_{subcyc}			2	—	8	t_W	* ²
Instruction cycle time				2	—	—	t_{cyc} t_{subcyc}	
Oscillation stabilization time (crystal resonator)	t_{rc}	OSC1, OSC2		—	—	10.0	ms	
Oscillation stabilization time (ceramic resonator)	t_{rc}	OSC1, OSC2		—	—	5.0	ms	
Oscillation stabilization time (on-chip oscillator)	t_{rc}			—	—	500	μs	
Oscillation stabilization time	t_{rcx}	X1, X2		—	—	2.0	s	
External clock high width	t_{CPH}	OSC1		23.8	—	—	ns	Figure 2.3.1
External clock low width	t_{CPL}	OSC1		23.8	—	—	ns	
External clock rise time	t_{CPr}	OSC1		—	—	15.0	ns	
External clock fall time	t_{CPf}	OSC1		—	—	15.0	ns	

■ Electrical Characteristics

Item	Symbol	Applicable Pins	Test Condition	Values			Unit	Reference Figure
				Min.	Typ.	Max.		
RES pin low width	t _{REL}	RES	At power-on and in modes other than those below	t _{rc}	—	—	ms	Figure 2.3.2
			In active mode and sleep mode	2500	—	—	ns	
Input pin high width	t _{IH}	NMI, TMIB1, IRQ0 to IRQ3, WKP0 to WKP5, TMCIV, TMRIV, TRGV, ADTRG, FTIOA0 to FTIOD0, FTIOA1 to FTIOD1		2	—	—	t _{cyc} t _{subcyc}	Figure 2.3.3
Input pin low width	t _{IL}	NMI, TMIB1, IRQ0 to IRQ3, WKP0 to WKP5, TMCIV, TMRIV, TRGV, ADTRG, FTIOA0 to FTIOD0, FTIOA1 to FTIOD1		2	—	—	t _{cyc} t _{subcyc}	
On-chip oscillator oscillation frequency	f _{RC}		V _{CC} = 3.3 V, Ta = 25°C, FSEL = 1, VCLSEL = 0	19.70	20.00	20.30	MHz	
			FSEL = 1, VCLSEL = 0	19.40	20.00	20.60		
			V _{CC} = 3.3 V, Ta = 25°C, FSEL = 0, VCLSEL = 0	15.84	16.00	16.16		
			FSEL = 0, VCLSEL = 0	15.52	16.00	16.48		

Notes: 1. When an external clock is input, the minimum frequency of the external clock oscillator is 4.0 MHz.
2. Determined by MA2 to MA0, SA1, and SA0 in system control register 2 (SYSCR2).

■ Electrical Characteristics

Table 2.2.2 I²C Bus Interface Timing

V_{CC} = 3.0 to 3.6 V, V_{SS} = 0.0 V, T_a = -20 to +75°C, unless otherwise indicated.

Item	Symbol	Test Condition	Values			Unit	Reference Figure
			Min.	Typ.	Max.		
SCL input cycle time	t _{SCL}		12t _{cyc} + 600	—	—	ns	Figure 2.3.4
SCL input high width	t _{SCLH}		3t _{cyc} + 300	—	—	ns	
SCL input low width	t _{SCLL}		5t _{cyc} + 300	—	—	ns	
SCL and SDA input fall time	t _{Sf}		—	—	300	ns	
SCL and SDA input spike pulse removal time	t _{SP}		—	—	1t _{cyc}	ns	
SDA input bus-free time	t _{BUF}		5t _{cyc}	—	—	ns	
Start condition input hold time	t _{STAH}		3t _{cyc}	—	—	ns	
Repeated start condition input setup time	t _{STAS}		3t _{cyc}	—	—	ns	
Setup time for stop condition input	t _{STOS}		3t _{cyc}	—	—	ns	
Data-input setup time	t _{SDAS}		1t _{cyc} +20	—	—	ns	
Data-input hold time	t _{SDAH}		0	—	—	ns	
Capacitive load of SCL and SDA	C _b		0	—	400	pF	
SCL and SDA output fall time	t _{Sf}		—	—	250	ns	

Table 2.2.3 Serial Communication Interface (SCI) Timing

V_{CC} = 3.0 to 3.6 V, V_{SS} = 0.0 V, T_a = -20 to +75°C, unless otherwise indicated.

Item	Symbol	Applicable Pins	Test Condition	Values			Unit	Reference Figure
				Min.	Typ.	Max.		
Input clock cycle	Asynchronous	SCK3		4	—	—	t _{cyc}	Figure 2.3.5
	Clock synchronous			6	—	—		
Input clock pulse width	t _{SCKW}	SCK3		0.4	—	0.6	t _{SCKW}	
Transmit data delay time (clock synchronous)	t _{TXD}	TXD		—	—	1	t _{cyc}	Figure 2.3.6
Receive data setup time (clock synchronous)	t _{RXS}	RXD		50.0	—	—	ns	
Receive data hold time (clock synchronous)	t _{RXH}	RXD		50.0	—	—	ns	

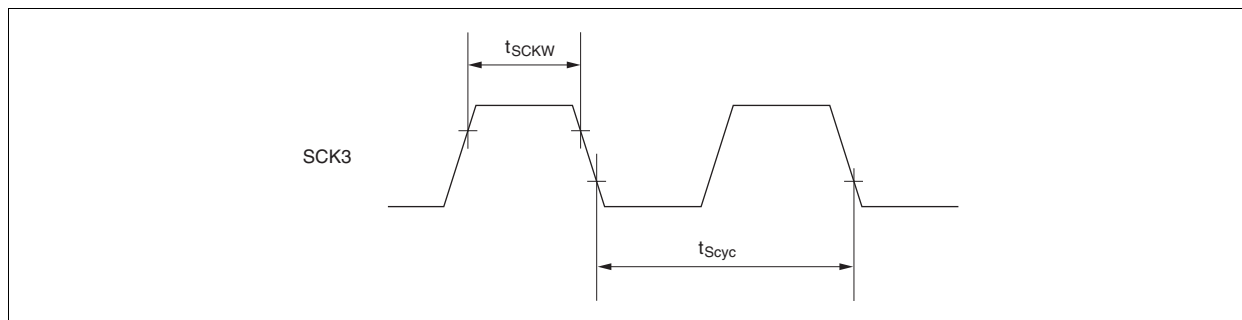


Figure 2.3.5 SCK3 Input Clock Timing

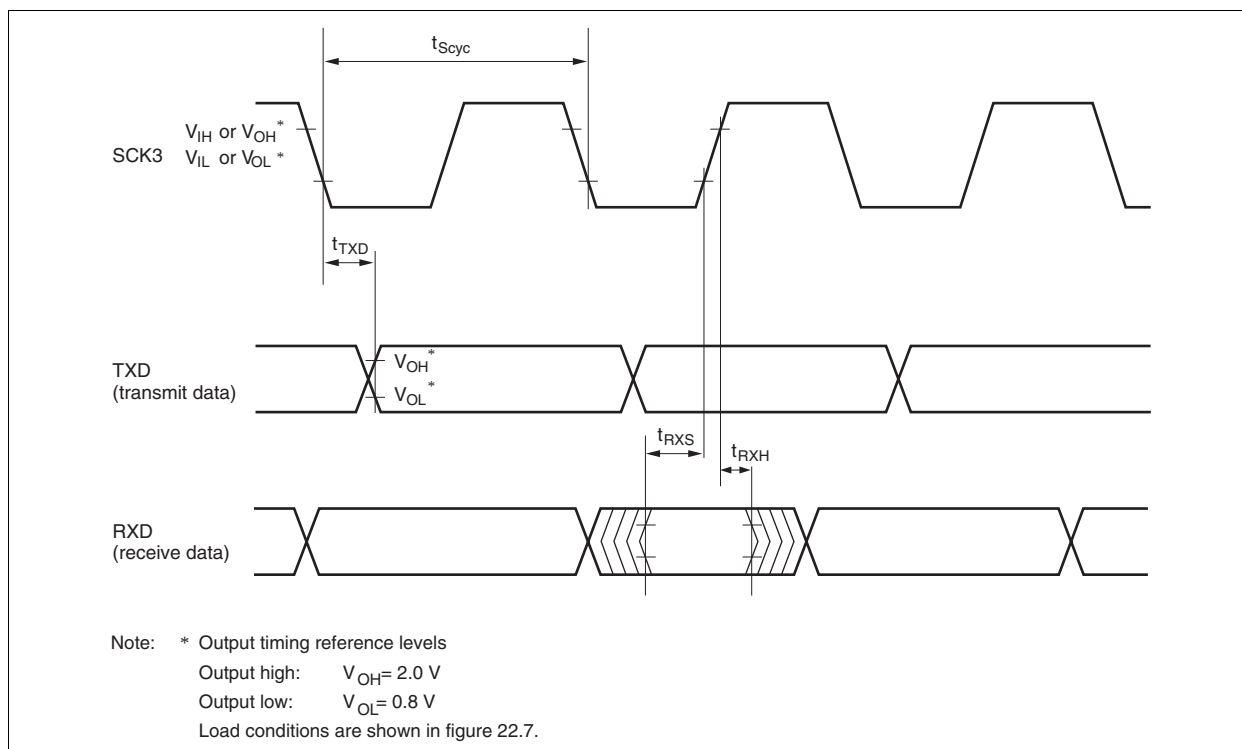
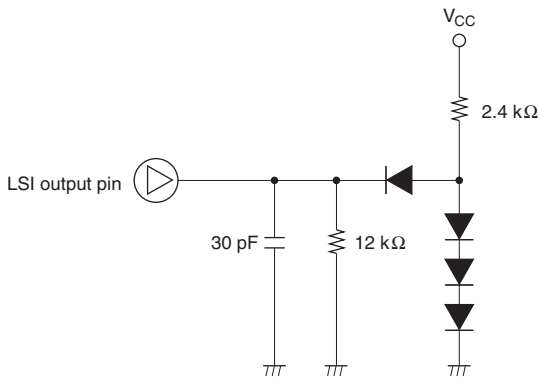


Figure 2.3.6 SCI Input/Output Timing in Clock Synchronous Mode



Output Load Circuit

2.4 A/D Converter Characteristics

Table 2.4.1 A/D Converter Characteristics

$V_{CC} = 3.0$ to 3.6 V, $V_{SS} = 0.0$ V, $T_a = -20$ to $+75^\circ\text{C}$, unless otherwise indicated.

Item	Symbol	Applicable Pins	Test Condition	Values			Unit	Reference Figure
				Min.	Typ.	Max.		
Analog power supply voltage	AV_{CC}	AV_{CC}		3.0	V_{CC}	3.6	V	* ¹
Analog input voltage	AV_{IN}	AN0 to AN7		$V_{SS} - 0.3$	—	$AV_{CC} + 0.3$	V	
Analog power supply current	AI_{OPE}	AV_{CC}	$AV_{CC} = 3.6$ V $f_{OSC} = 16$ MHz	—	—	2.0	mA	
	AI_{STOP1}	AV_{CC}		—	50	—	μA	* ² Reference value
	AI_{STOP2}	AV_{CC}		—	—	5.0	μA	* ³
Analog input capacitance	CA_{IN}	AN0 to AN7		—	—	30.0	pF	
Permissible signal source impedance	RA_{IN}	AN0 to AN7		—	—	5.0	k Ω	
Resolution (data length)				10	10	10	bit	
Conversion time (single mode)			$AV_{CC} = 3.0$ to 3.6 V	134	—	—	t_{cyc}	
Nonlinearity error				—	—	± 7.5	LSB	
Offset error				—	—	± 7.5	LSB	
Full-scale error				—	—	± 7.5	LSB	
Quantization error				—	—	± 0.5	LSB	
Absolute accuracy				—	—	± 8.0	LSB	

Notes: 1. Set $AV_{CC} = V_{CC}$ when the A/D converter is not used.
2. AI_{STOP1} is the current in active and sleep modes while the A/D converter is idle.
3. AI_{STOP2} is the current at reset and in standby, subactive, and subsleep modes while the A/D converter is idle.

2.5 External Oscillators

There are two methods to supply external clock pulses into this LSI: connecting a crystal or ceramic resonator, and an external clock. Oscillation pins OSC1 and OSC2 are common with general ports PC0 and PC1, respectively.

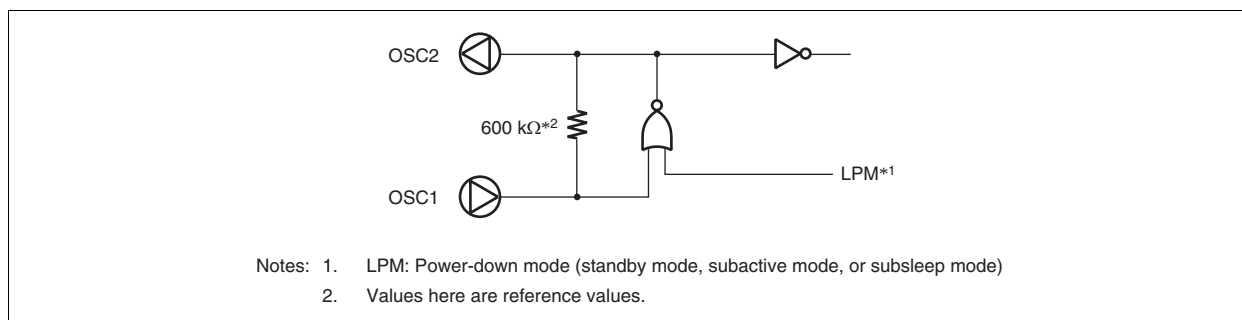


Figure 2.5.1 Block Diagram of External Clock Oscillator

2.5.1 Connecting Crystal Resonator

Figure 2.5.2 shows an example of connecting a crystal resonator. An AT-cut parallel-resonance crystal resonator should be used. Figure 2.5.3 shows the equivalent circuit of a crystal resonator. A resonator having the characteristics given in table 2.5.1 should be used.

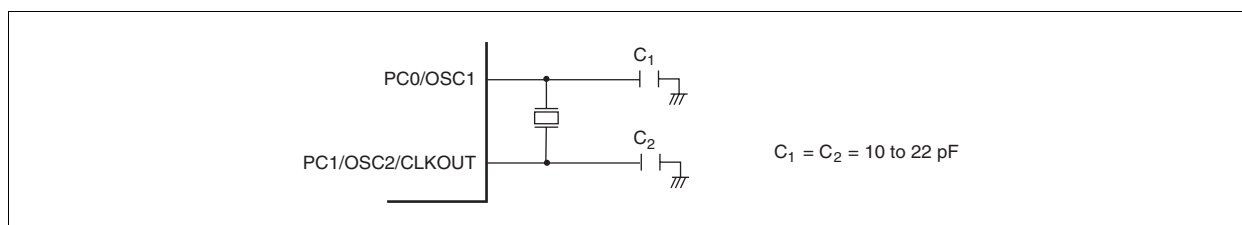


Figure 2.5.2 Example of Connection to Crystal Resonator

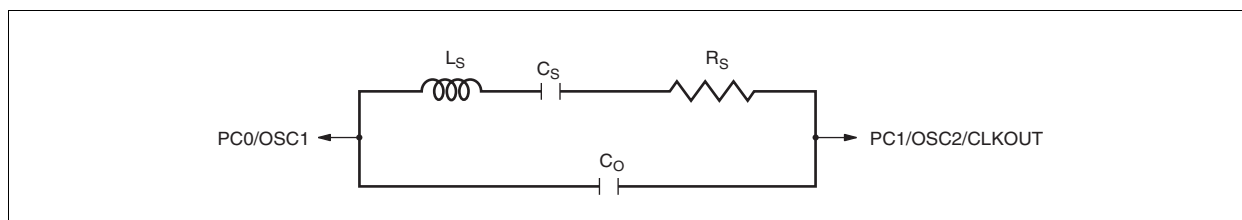


Figure 2.5.3 Equivalent Circuit of Crystal Resonator

Table 2.5.1 Crystal Resonator Parameters

Frequency (MHz)	4	8	10	16	20
R_S (Max.)	120 Ω	80 Ω	60 Ω	50 Ω	40 Ω
C_O (Max.)	70 pF				

(1) Connecting Ceramic Resonator

Figure 2.5.4 shows an example of connecting a ceramic resonator.

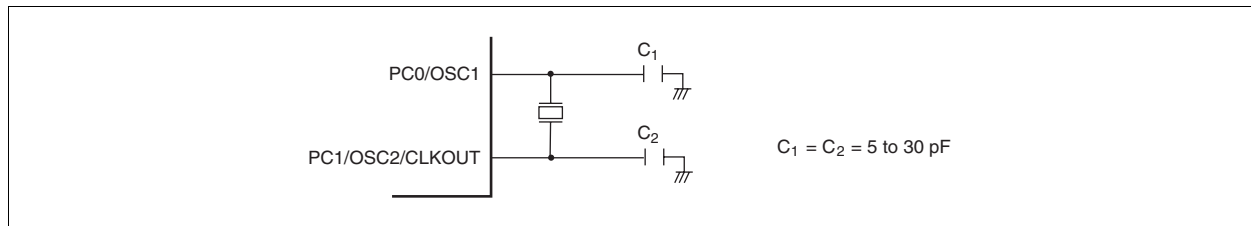


Figure 2.5.4 Example of Connection to Ceramic Resonator

(2) Inputting External Clock

To use the external clock, input the external clock on pin OSC1. Figure 2.5.5 shows an example of connection. The duty cycle of the external clock signal must range from 45 to 55%.

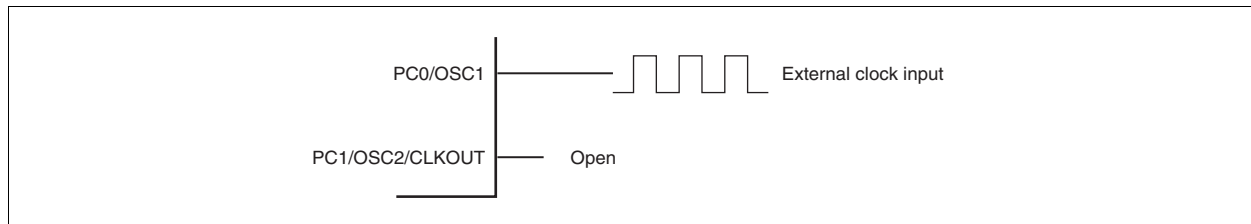


Figure 2.5.5 Example of External Clock Input

2.5.2 Subclock Oscillator

Figure 2.5.6 shows a block diagram of the subclock oscillator.

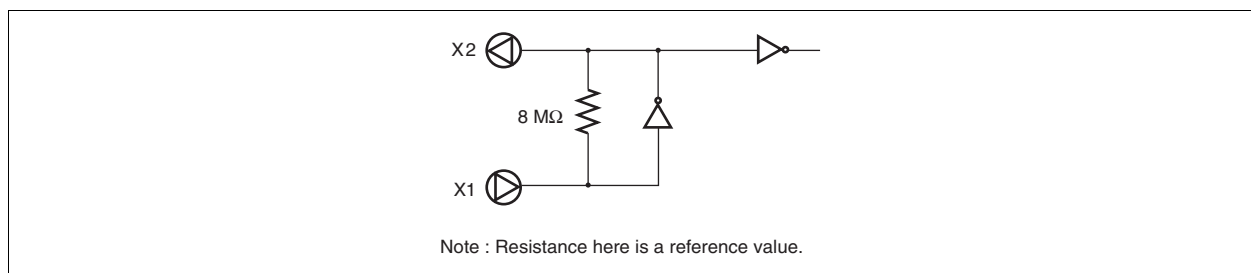


Figure 2.5.6 Block Diagram of Subclock Oscillator

(1) Connecting 32.768-kHz Crystal Resonator

Clock pulses can be supplied to the subclock divider by connecting a 32.768-kHz crystal resonator, as shown in figure 2.5.7. Figure 2.5.8 shows the equivalent circuit of the 32.768-kHz crystal resonator.

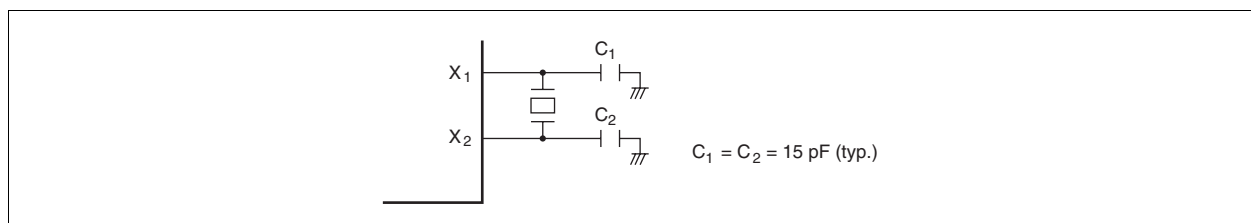


Figure 2.5.7 Typical Connection to 32.768-kHz Crystal Resonator

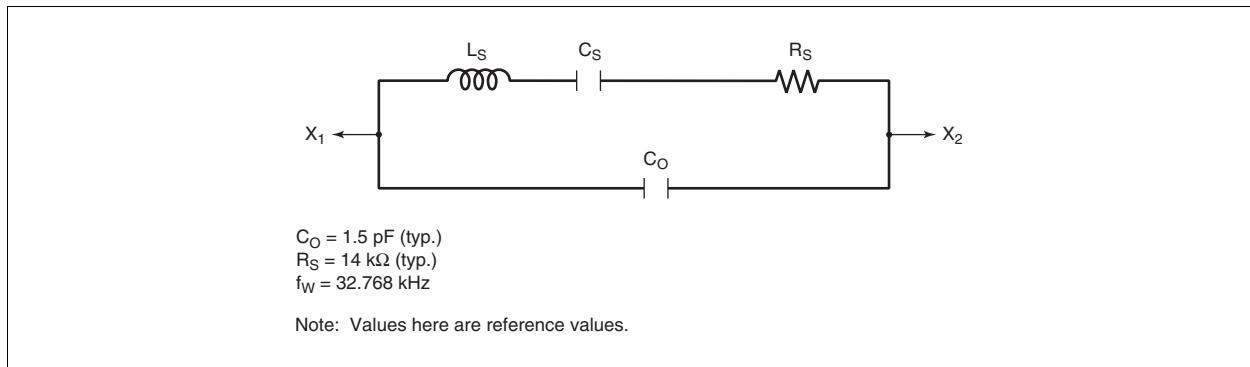


Figure 2.5.8 Equivalent Circuit of 32.768-kHz Crystal Resonator

(2) Pin Connection when Not Using Subclock

When the subclock is not used, connect pin X1 to VCL or VSS and leave pin X2 open, as shown in figure 2.5.9.

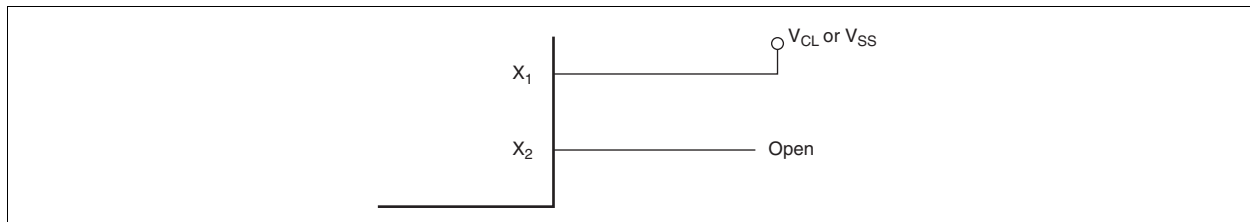


Figure 2.5.9 Pin Connection when not Using Subclock

2.5.3 Usage Notes

(1) Note on Resonators

Resonator characteristics are closely related to board design and should be carefully evaluated by the user, referring to the examples shown in this section. Resonator circuit parameters will differ depending on the resonator element, stray capacitance of the PCB, and other factors. Suitable values should be determined in consultation with the resonator element manufacturer. Design the circuit so that the resonator element never receives voltages exceeding its maximum rating.

(2) Notes on Board Design

When using a crystal resonator (ceramic resonator), place the resonator and its load capacitors as close as possible to pins OSC1 and OSC2. Other signal lines should be routed away from the oscillator circuit to prevent induction from interfering with correct oscillation (see figure 2.5.10).

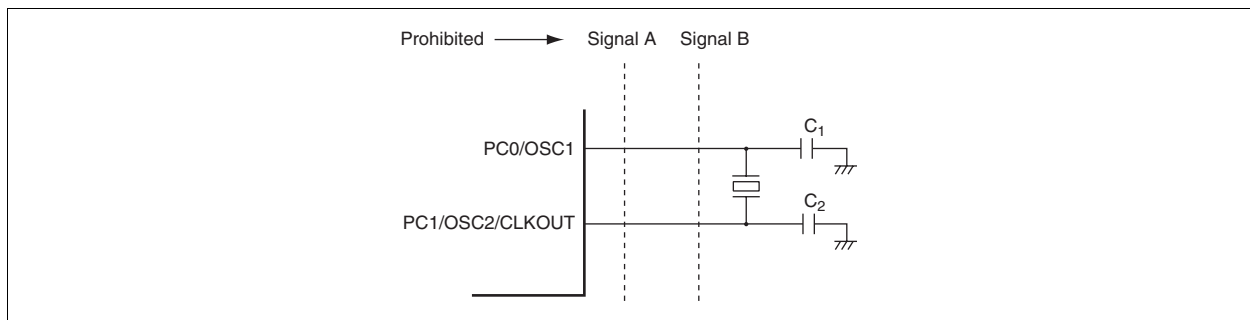


Figure 2.5.10 Example of Incorrect Board Design

2.6 Watchdog Timer Characteristics**Table 2.6.1 Watchdog Timer Characteristics**

$V_{CC} = 3.0$ to 3.6 V, $V_{SS} = 0.0$ V, $T_a = -20$ to $+75^{\circ}\text{C}$, unless otherwise indicated.

Item	Symbol	Applicable Pins	Test Condition	Values			Unit	Reference Figure
				Min.	Typ.	Max.		
On-chip oscillator overflow time	t_{OVF}			0.2	0.4	—	s	*

Note: * Time until an internal reset is generated after the counter counts from 0 to 255 when the on-chip oscillator is selected

2.7 ROM Characteristics

2.7.1 Flash Memory Characteristics

Table 2.7.1 Flash Memory Characteristics

$V_{CC} = 3.0$ to 3.6 V, $V_{SS} = 0.0$ V, $T_a = -20$ to $+75^{\circ}\text{C}$, unless otherwise indicated.

Item	Symbol	Test Condition	Values			Unit
			Min.	Typ.	Max.	
Programming time (per 128 bytes)* ¹ * ² * ⁴	t_P		—	7.0	10.0	ms
Erase time (per block) * ¹ * ³ * ⁶	t_E		—	10.0	20.0	ms
Reprogramming count	N_{WEC}		1000	10000	—	Times
Programming	Wait time after setting SWE bit* ¹	x	1	—	—	μs
	Wait time after setting PSU bit* ¹	y	50	—	—	μs
	Wait time after setting P bit * ¹ * ⁴	z1	$1 \leq n \leq 6$	28	30	μs
		z2	$7 \leq n \leq 1000$	198	200	μs
		z3	Additional-programming	8	10	μs
	Wait time after clearing P bit* ¹	α	5	—	—	μs
	Wait time after clearing PSU bit* ¹	β	5	—	—	μs
	Wait time after setting PV bit* ¹	γ	4	—	—	μs
	Wait time after dummy write* ¹	ε	2	—	—	μs
	Wait time after clearing PV bit* ¹	η	2	—	—	μs
	Wait time after clearing SWE bit* ¹	θ	100	—	—	μs
Maximum programming count * ¹ * ⁴ * ⁵	N		—	—	1000	Times

Data hold time			
	Reprogramming count	Memory address	Data hold time*⁸
	1000 Times	H'000000 ~ H'01FFFF	10 year
	10000 Times	H'000000 ~ H'000FFF	3 month

■ Electrical Characteristics

Item		Symbol	Test Condition	Values			Unit
				Min.	Typ.	Max.	
Erasing	Wait time after setting SWE bit ^{*1}	x		1	—	—	μs
	Wait time after setting ESU bit ^{*1}	y		100	—	—	μs
	Wait time after setting E bit ^{*1*6}	z		10	—	100	ms
	Wait time after clearing E bit ^{*1}	α		10	—	—	μs
	Wait time after clearing ESU bit ^{*1}	β		10	—	—	μs
	Wait time after setting EV bit ^{*1}	γ		20	—	—	μs
	Wait time after dummy write ^{*1}	ε		2	—	—	μs
	Wait time after clearing EV bit ^{*1}	η		4	—	—	μs
	Wait time after clearing SWE bit ^{*1}	θ		100	—	—	μs
	Maximum erase count ^{*1*6*7}	N		—	—	120	Times

- Notes:
1. Make the time settings in accordance with the program/erase algorithms.
 2. The programming time for 128 bytes. (Indicates the total time for which the P bit in flash memory control register 1 (FLMCR1) is set. The program-verify time is not included.)
 3. The time required to erase one block. (Indicates the time for which the E bit in flash memory control register 1 (FLMCR1) is set. The erase-verify time is not included.)
 4. Programming time maximum value ($t_P(\max.)$) = wait time after P bit setting (z) × maximum programming count (N)
 5. Set the maximum programming count (N) according to the actual set values of z1, z2, and z3 so that it does not exceed the programming time maximum value ($t_P(\max.)$). The wait time after setting P bit (z1, z2) should be changed as follows according to the value of the programming count (n).
Programming count (n)
 $1 \leq n \leq 6$ z1 = 30 μs
 $7 \leq n \leq 1000$ z2 = 200 μs
 6. Erase time maximum value ($t_E(\max.)$) = wait time after E bit setting (z) × maximum erase count (N)
 7. Set the maximum erase count (N) according to the actual set value of (z) so that it does not exceed the erase time maximum value ($t_E(\max.)$).
 8. The data hold time includes time that the power supply is off or the clock is not supplied.

2.7.2 Flash Memory Programming/Erasing

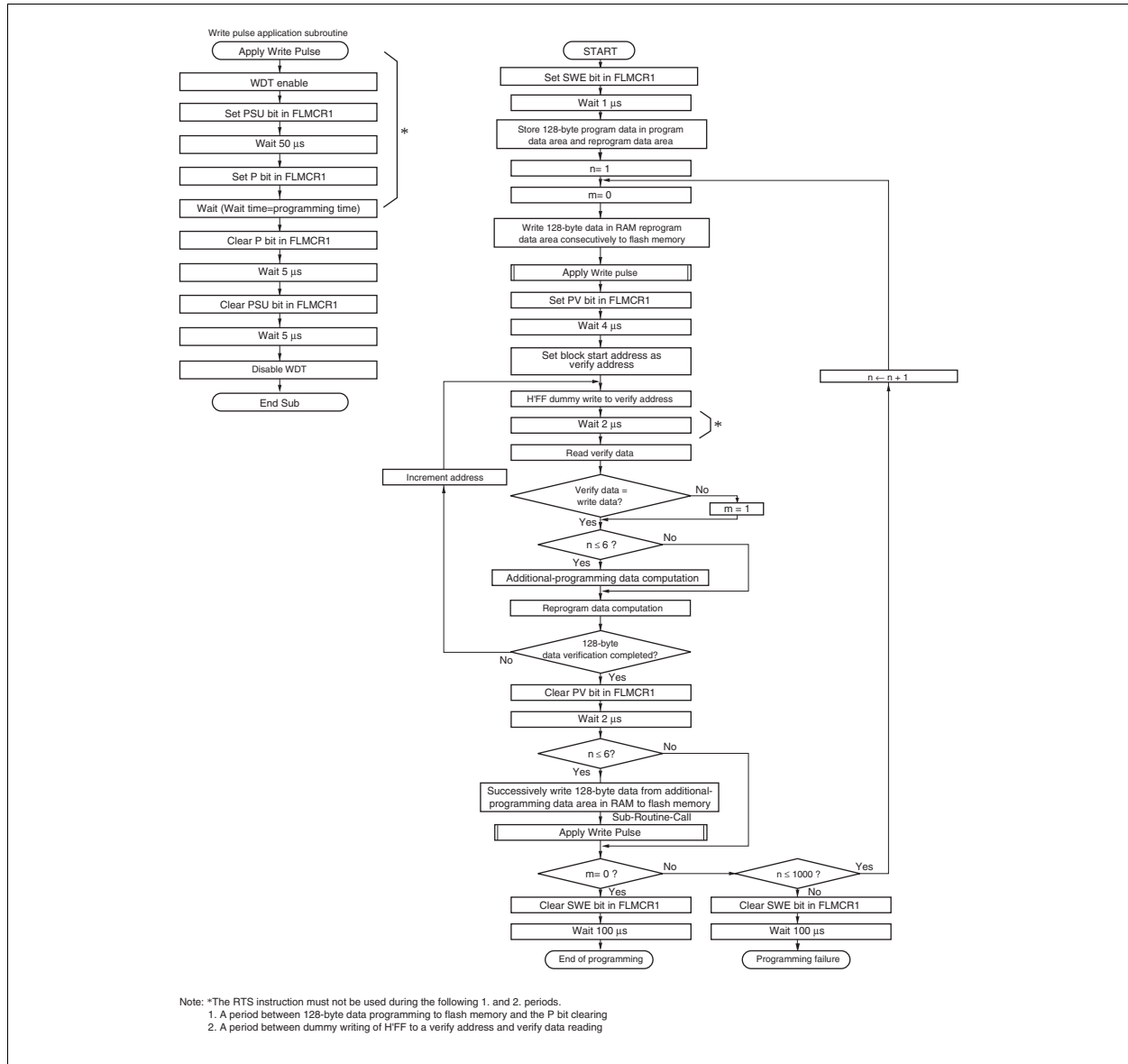


Figure 2.7.1 Program/Program-Verify Flowchart

Table 2.7.2 Reprogram Data Computation Table

Program Data	Verify Data	Reprogram Data	Comments
0	0	1	Programming completed
0	1	0	Reprogram bit
1	0	1	—
1	1	1	Remains in erased state

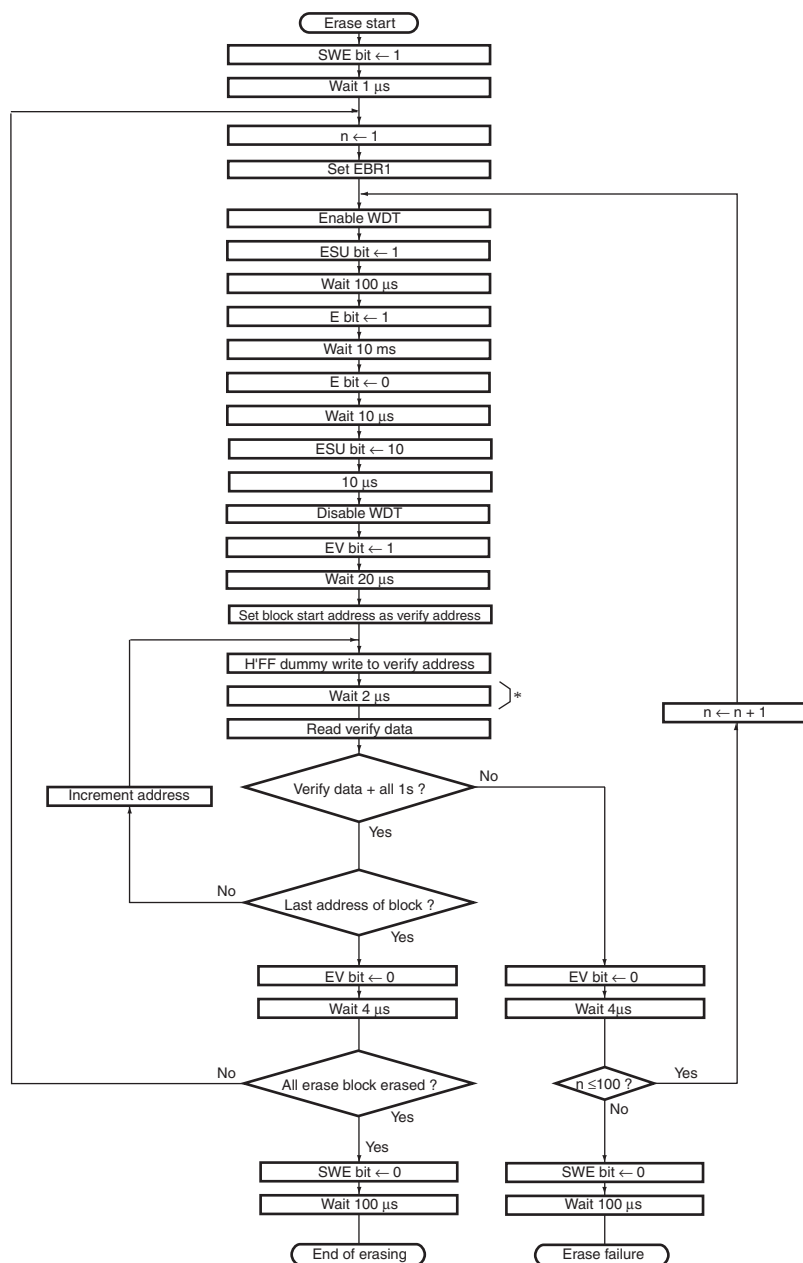
Table 2.7.3 Additional-Program Data Computation Table

Reprogram Data	Verify Data	Additional-Program Data	Comments
0	0	0	Additional-program bit
0	1	1	No additional programming
1	0	1	No additional programming
1	1	1	No additional programming

Table 2.7.4 Programming Time

n (Number of Writes)	Programming Time	In Additional Programming	Comments
1 to 6	30	10	
7 to 1,000	200	—	

Note: Time shown in μ s.



Note: *The RTS instruction must not be used during a period between dummy writing of H'FF to a verify address and verify data reading.

Figure 2.7.2 Erase/Erase-Verify Flowchart

2.9 Power-Supply-Voltage Detection Circuit Characteristics

2.9.1 Power-Supply-Voltage Detection Circuit Characteristics

Table 2.9.1 Power-Supply-Voltage Detection Circuit Characteristics

$V_{SS} = 0.0\text{ V}$, $T_a = -20\text{ to }+75^\circ\text{C}$, unless otherwise indicated.

Item	Symbol	Values			Unit
		Min.	Typ.	Max.	
Power-supply falling detection voltage	Vint (D)	2.8	2.9	3.05	V
Power-supply rising detection voltage	Vint (U)	2.9	3.0	3.15	V
Reset detection voltage 1*	Vreset1	—	2.3	2.6	V
Lower-limit voltage of LVDR operation	V _{LVDRmin}	1.0	—	—	V

Note: * This voltage should be used when the falling and rising voltage detection function is used.

2.9.2 LVDI External Input Voltage Detection Circuit Characteristics

Table 2.9.2 LVDI External Input Voltage Detection Circuit Characteristics

$V_{CC} = 3.0\text{ to }3.6\text{ V}$, $AV_{CC} = 3.0\text{ to }3.6\text{ V}$, $V_{SS} = 0.0\text{ V}$, $T_a = -20\text{ to }+75^\circ\text{C}$

Item	Symbol	Test Condition	Values			Unit
			Min.	Typ.	Max.	
ExtD/ExtU input detection voltage	Vexd		0.95	1.15	1.35	V
ExtD/ExtU input voltage range	VextD/VextU	VextD > VextU	-0.3	—	Lower voltage of $AV_{CC} + 0.3$ or $V_{CC} + 0.3$	V

2.9.3 Power-On Reset Circuit Characteristics

Table 2.9.3 Power-On Reset Circuit Characteristics

$V_{SS} = 0.0\text{ V}$, $T_a = -20\text{ to }+75^\circ\text{C}$, unless otherwise indicated.

Item	Symbol	Test Condition	Values			Unit
			Min.	Typ.	Max.	
Pull-up resistance of $\overline{RES}$ pin	R _{RES}		100	150	—	kΩ
Power-on reset start voltage*	V _{por}		—	—	100	mV

Note: * The power-supply voltage (V_{CC}) must fall below $V_{por} = 100\text{ mV}$ and then rise after charge of the $\overline{RES}$ pin is removed completely. In order to remove charge of the $\overline{RES}$ pin, it is recommended that the diode be placed in the V_{CC} side. If the power-supply voltage (V_{CC}) rises from the point over 100 mV , a power-on reset may not occur.

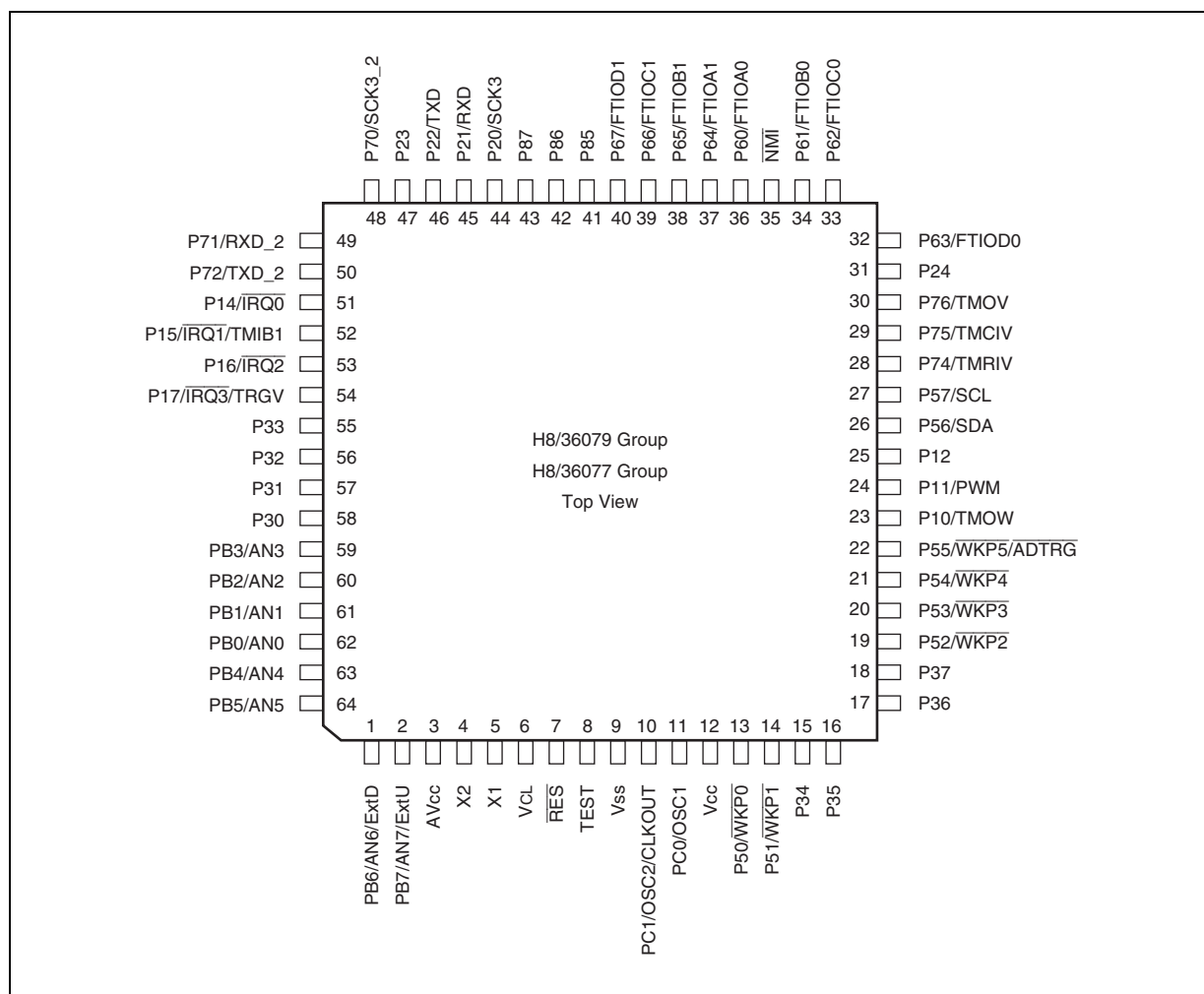
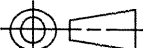
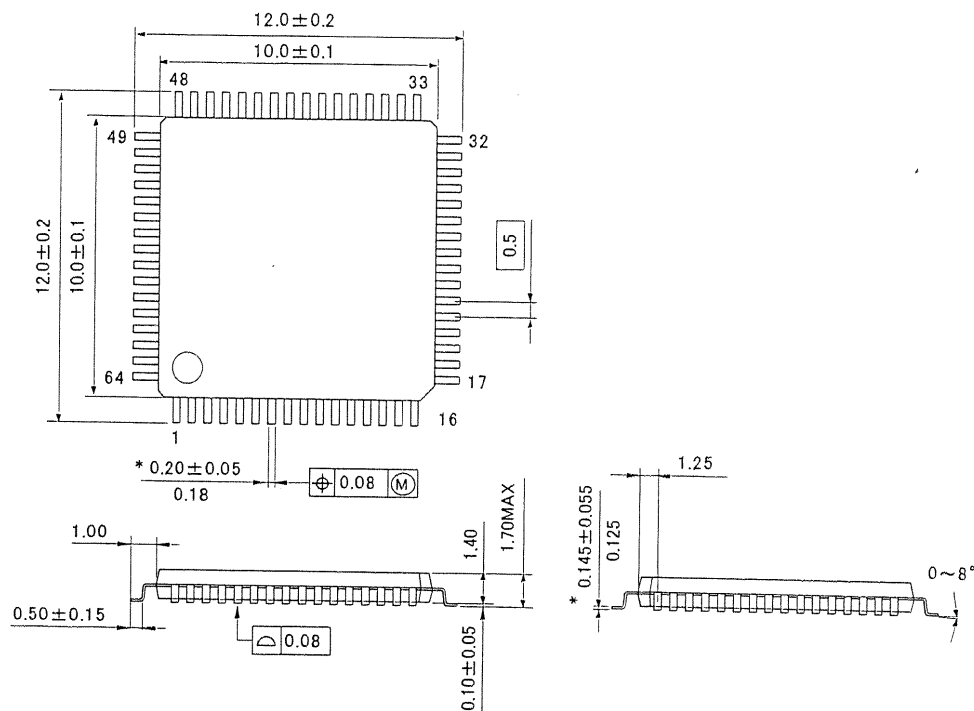


Figure 1 Pin Assignments (FP-64K, FP-64A)

D.CHKD

REMARKS												
DWN.	M. TSUGANE	2004.03.17	PROJECTION	TITLE					DWG. STAMP			
CHKD.	M. YAMADA	2004.03.18		FTR-OUTLN								
APPD.	F. Ito	2004.03.18	SCALE NTS	顧客向け外形寸法図								
				SD	TYPE	D.D	CLASS.	MD	WORK-SPEC No.			
				E	50	AN	528	M	PKG FTR			
								1190				
Renesas Technology Corp.									SH.			
				343					4Q01699			
									1			
									E			



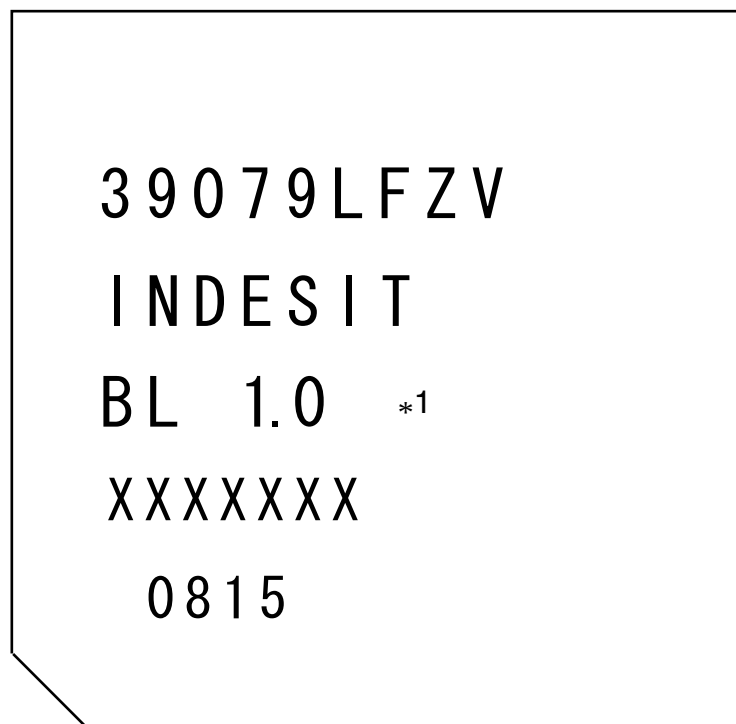
*
めっき厚含み寸法

素材寸法

*
Dimension including the plating thickness
Base material dimension

(単位 unit:mm)

パッケージコード (Package CODE)	FP-64K,FP-64KV
JEITAコード (JEITA CODE)	EDR-7311準拠
JEDECコード (JEDEC CODE)	_____
重量(g) (mass)	0.3g



39079LFZV : Type
INDESIT : Customer's Parts No.1
BL 1.0 : Customer's Parts No.2
0815 : Production Lot Code (EIA Code)
(A number of four figures)
XXXXXXX : Trace Code

Note: 1. In case of reprogramming chips that are already marked with Customer's Parts No.2 (boot version), a dot will be added right side boot version.

Figure 1 Mark Specification Example

Functional Block Diagram

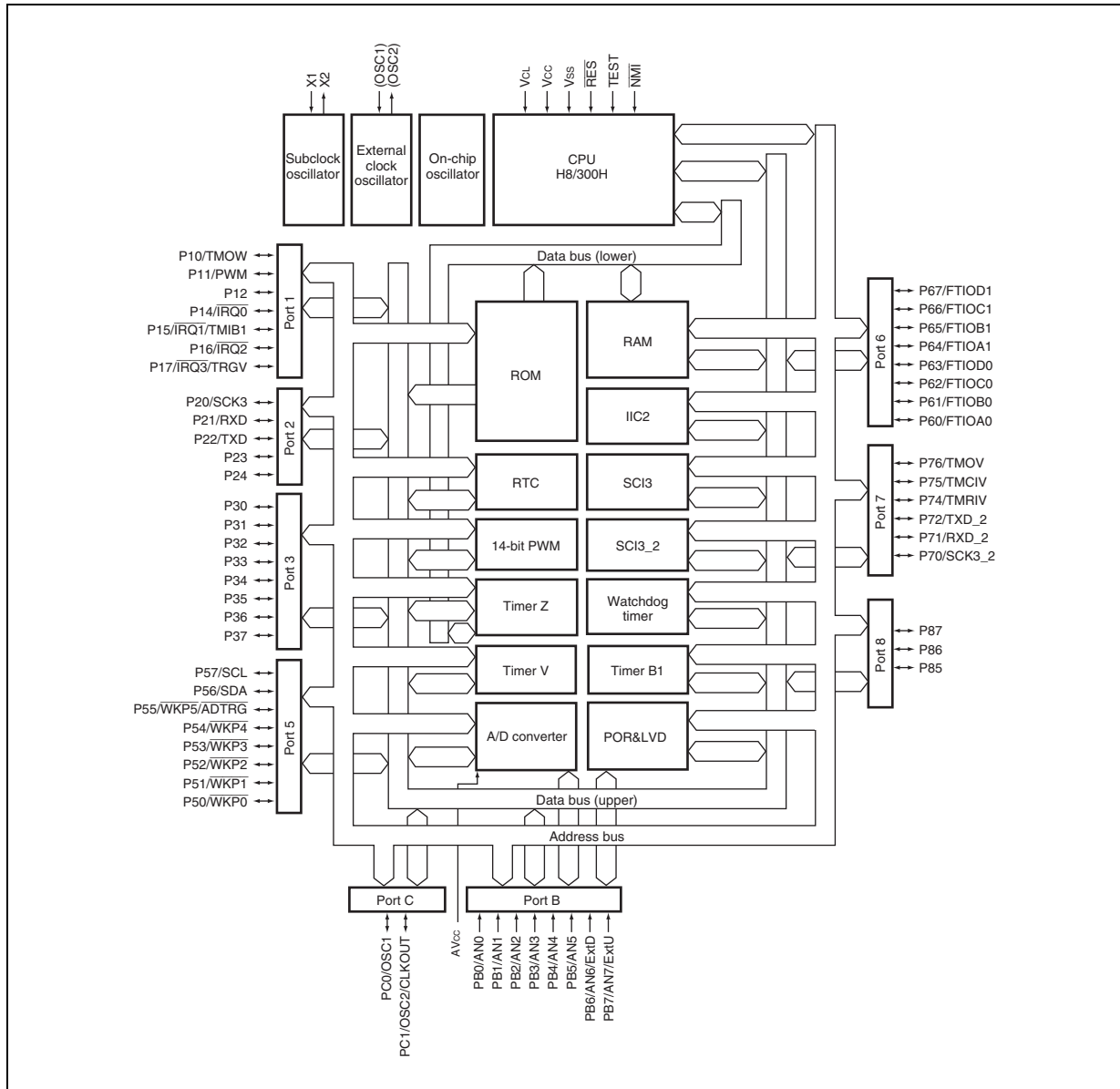


Figure 1 Functional Block Diagram

(1) Problems with the delivery

If any problems occur regarding the quality of supplied product etc, they will be solved by negotiations between your company and Renesas Technology Corp.

(2) Problems and revision to the specifications

If any problems occur, or if any revision to the specifications is necessary, they will be solved by negotiations between your company and Renesas Technology Corp.

(3) Production lot number

EIA code

Indicate it with 4 digit.

Indicate it with under 2 digit of the year, and week of the year.

For example, number of 0508 is lot manufactured at the 08th week of 2005 years.

(4) Packing and indication

Semiconductor products applicable to this specification are packed in inner package to keep out foreign matters. This package includes the manufacture's abbreviations, lot number and product's name on it.

1.1 Address Space and Memory Map

Figure 1.1 shows the memory map.

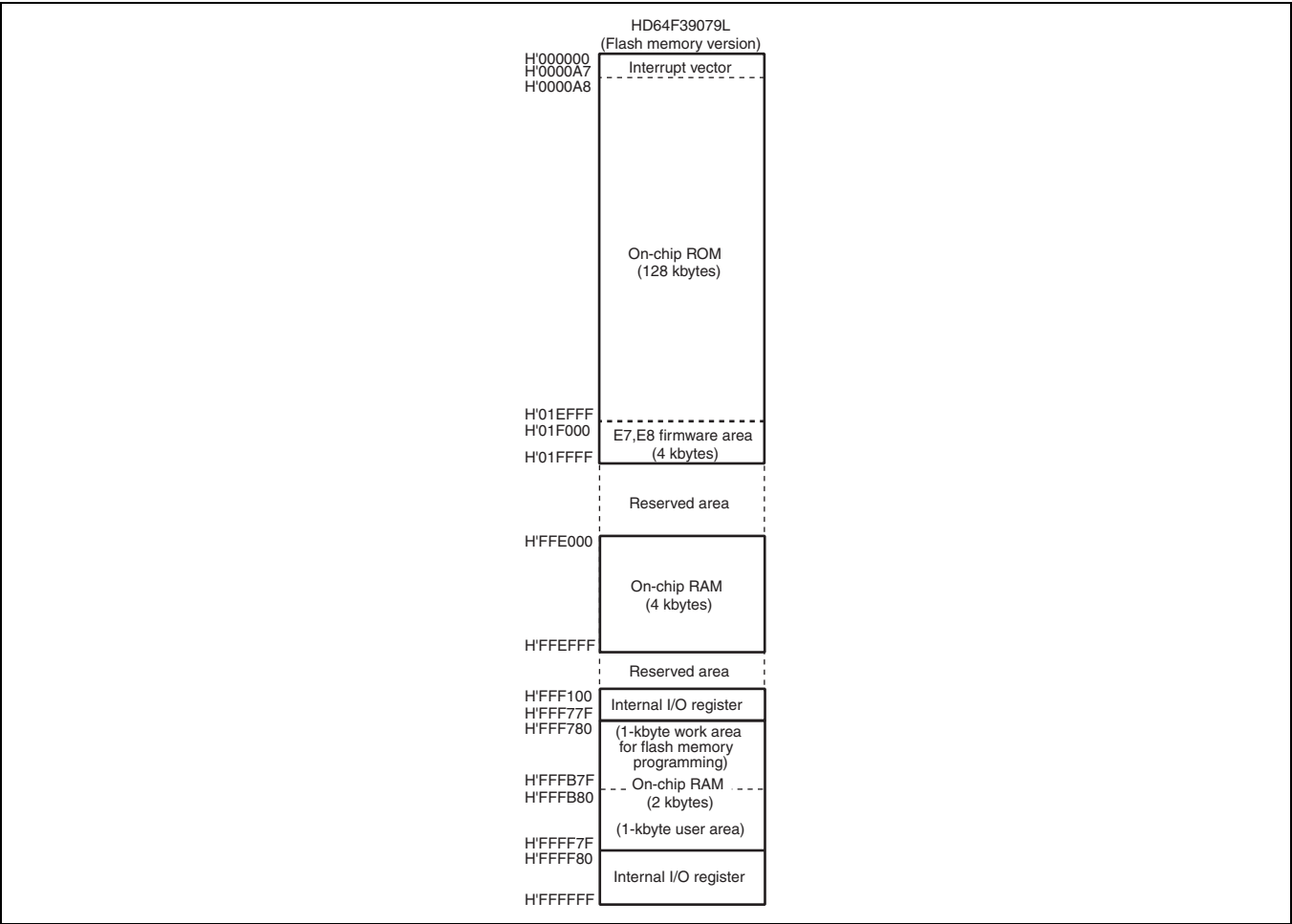


Figure 1.1 Memory Map

1.2 Block Configuration

Figure 1.2 shows the block configuration of flash memory. The thick lines indicate erasing units, the narrow lines indicate programming units, and the values are addresses. The 128-kbyte flash memory is divided into 1 kbyte × 4 blocks, 28 kbytes × 1 block and 32 kbytes × 3 blocks. Erasing is performed in these units.

Programming is performed in 128-byte units starting from an address with lower eight bits H'00 or H'80.

Erasing unit: 1 kbyte	H'000000	H'000001	H'000002	← Programming unit: 128 bytes →	H'00007F
	H'000380	H'000381	H'000382		H'0003FF
Erasing unit: 1 kbyte	H'000400	H'000401	H'000402	← Programming unit: 128 bytes →	H'00047F
	H'000780	H'000781	H'000782		H'0007FF
Erasing unit: 1 kbyte	H'000800	H'000801	H'000802	← Programming unit: 128 bytes →	H'00087F
	H'000B80	H'000B81	H'000B82		H'000BFF
Erasing unit: 1 kbyte	H'000C00	H'000C01	H'000C02	← Programming unit: 128 bytes →	H'000C7F
	H'000F80	H'000F81	H'000F82		H'000FFF
Erasing unit: 28 kbytes	H'001000	H'001001	H'001002	← Programming unit: 128 bytes →	H'00107F
	H'007F80	H'007F81	H'007F82		H'007FFF
Erasing unit: 32 kbytes	H'008000	H'008001	H'008002	← Programming unit: 128 bytes →	H'00807F
	H'00FF80	H'00FF81	H'00FF82		H'00FFFF
Erasing unit: 32 kbytes	H'010000	H'010001	H'010002	← Programming unit: 128 bytes →	H'01007F
	H'017F80	H'017F81	H'017F82		H'017FFF
Erasing unit: 32 kbytes	H'018000	H'018001	H'018002	← Programming unit: 128 bytes →	H'01807F
	H'01FF80	H'01FF81	H'01FF82		H'01FFFF

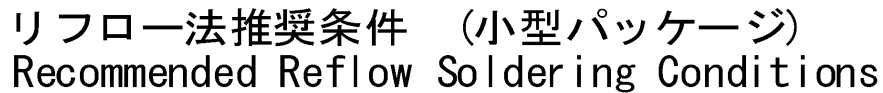
Figure 1.2 Block Configuration of Flash Memory

■ Address Map

1.2.1 Erase Block Register 1 (EBR1)

EBR1 specifies the flash memory erase area block. EBR1 is initialized to H'00 when the SWE bit in FLMCR1 is 0. Do not set more than one bit at a time, as this will cause all the bits in EBR1 to be automatically cleared to 0.

Bit	Bit Name	Initial Value	R/W	Description
7	EB7	0	R/W	When this bit is set to 1, 32 kbytes of H'018000 to H'01FFFF will be erased.
6	EB6	0	R/W	When this bit is set to 1, 32 kbytes of H'010000 to H'017FFF will be erased.
5	EB5	0	R/W	When this bit is set to 1, 32 kbytes of H'008000 to H'00FFFF will be erased.
4	EB4	0	R/W	When this bit is set to 1, 28 kbytes of H'001000 to H'007FFF will be erased.
3	EB3	0/1	R/W	When this bit is set to 1, 1 kbyte of H'000C00 to H'000FFF will be erased.
2	EB2	0/1	R/W	When this bit is set to 1, 1 kbyte of H'000800 to H'000BFF will be erased.
1	EB1	0/1	R/W	When this bit is set to 1, 1 kbyte of H'000400 to H'0007FF will be erased.
0	EB0	0/1	R/W	When this bit is set to 1, 1 kbyte of H'000000 to H'0003FF will be erased.

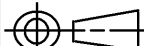


After opening the moisture proof packing, parts must be installed at the condition , the keeping condition after opening dry packing, against re- moisturized. If the device has been stored longer than the specified time after opening packing, parts must be baked at the condition of the baking condition.

-
- Package surface temperature
- 時間 time
- 150~180°C
- 90±30s
- 1~5°C/s
- 30~50s
- 260°C max
- 230°C
- 1~4°C/s

＜小型パッケージのエアリフロー、N2リフロー推奨条件＞

- | | |
|-------|---|
| MHSM | 1 |
| Mタカサキ | D |
| MチョウL | D |
| MW | D |
| MM3 | 1 |
| MM2 | 1 |
| MM1 | 1 |
| MA | 1 |
| MQ | 1 |

MQ		1												REMARKS		Pb-Free																			
PROVI.		co												DWN.				PROJECTION		TITLE										DWG.STAMP					
SECT.		py																		FTR-REFL-COND															
														CHKD.				SCALE NTS				顧客向けリフロー条件													
														APPD.						REGD.		SD		TYPE		D.D		CLASS.		MD		WORK-SPEC No.			
																						E		5Z		B2		528		E		PKG FTR			
																												4179							
																														SH.					
																														1					
																														F					
D.CHKD				D		C		B		A		GENERAL		区分 (GROUP)		Renesas Technology Corp.										343 4Q01178									

APPD.	R.KIMOTO
CHKD.	R.KIMOTO
REVD.	M.YAMADA
DATE	2005.06.27

REVISIONS	P.1, W#PKGFTTR, S#4502
SYM/NPL	1 3

MHSD	D
MチヨウL	D
MW	D
MQ	1
MM3	1
MM2	1
MM1	1
MHSM	1
MA	1

PROVI.	co
SECT.	py
D.CHKD	D C B A

3

ベークについて(厚型) Baking Process (Thick type)

実装前のベーク(乾燥)処理について

About the baking process (Moisture removal process) before soldering

1) ベーク処理を必要とする場合 Baking is necessary in the following cases.

A) 防湿包装開封時に、インジケータカードの30%スポットが ピンクに変色している場合

When the 30% spot on the humidity indicator card turns pink, when the moisture-proof bag is opened.

B) 防湿包装開封後、規定の保管条件を超過した場合

When the storage conditions exceed the stipulation after the moisture-proof bag is opened.

2) 推奨ベーク条件 Recommended baking condition

	ベーク温度 Baking Temperature	ベーク時間 Baking Time	繰り返しベーク Repetitive Baking
厚型 (Thick type)	125°C±5°C	16 to 24 hours	累計で96時間以内 Total of 96 hours or less

ベークの際は、耐熱性のあるトレイなどで処理してください。

なお、耐熱トレイには、「HEAT PROOF」または耐熱温度の表示がありますので、
処理の前にご確認ください。

Be sure to use heatproof trays, etc., when performing the baking process.

Heatproof trays are marked with the words "HEAT PROOF"

or carry an indication of their maximum temperature rating.

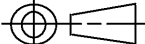
Confirm these markings before performing the baking process.

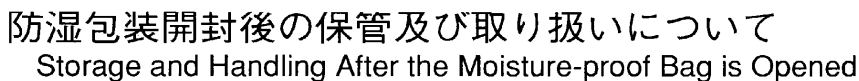
REMARKS		厚型			
DWN.	M.YAMADA	2005.06.24			
CHKD.	R.KIMOTO	2005.06.24			
APPD.	R.KIMOTO	2005.06.24			
TITLE		FTR-BAKE-COND			
顧客向けベーク条件		DWG.STAMP			
SD	TYPE	D.D	CLASS.	MD	WORK-SPEC No.
E	50	AN	528	E	PKGFTTR
					4502
Renesas Technology Corp.					SH.
343 4Q00874					1
					E

防湿包装開封前の保管期限は5～35℃、85%RH以下で2年です。
The time limit to leave the packages in a dry pack is 2 years,
provided that the temperature is between 5 to 35℃
and the relative humidity is 85% or less.

MHSD	D
MチヨウL	D
MW	D
MQ	1
MM3	1
MM2	1
MM1	1
MHSM	1
MA	1

PROVI. SECT.	co py
D.CHKD	

					REMARKS		防湿包装開封前								
D	C	B	A	GENERAL	Gr.	区分(GROUP)	DWN.		PROJECTION 	TITLE			DWG.STAMP		
							CHKD.			FTR-STRG-COND					
							APPD.			SCALE NTS	REGD.	顧客向け保管条件			
							SD	TYPE	D.D	CLASS.	MD	WORK-SPEC No.			
							E	50	AN	528	E	PKGFTTR			
											4782				
							Renesas Technology Corp.					SH.			
							343 4Q00876					1			
												E			



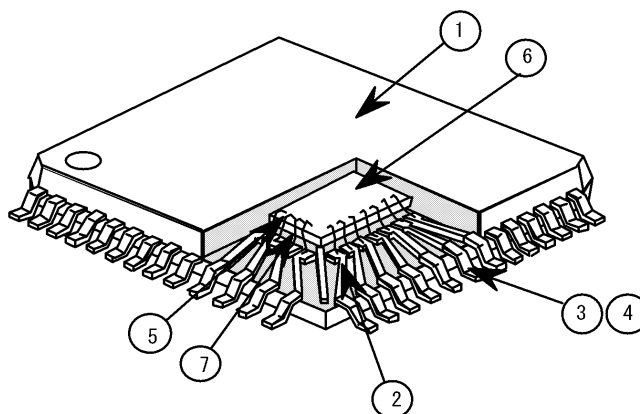
防湿包装開封後は吸湿を避けるため、下記条件にて保管してください。
Parts must be kept as below after opening dry packing against re-moisturized.

項目	条件	備 考
温度 Temperature	5℃～30℃	
湿度 Humidity	60%RH以下 60% RH or less	
時間＊ Time	168時間以内 168 hours or less	＊ 開封後～最終リフローはんだ付け完了までの時間 This refers to the total time between opening the moisture-proof bag and completing the final reflow soldering process.

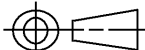
MチヨウL	D
MW	D
MQ	1
MM3	1
MM2	1
MM1	1
MHSM	1
MA	1

PROVI. co
SECT. py

REMARKS		防湿包装開封後								
DWN.			PROJECTION	TITLE FTR-STRG-COND 顧客向け保管条件					DWG.STAMP	
CHKD.			SCALE NTS							
APPD.				REGD.	SD	TYPE	D.D	CLASS.	MD	WORK-SPEC No.
Renesas Technology Corp.					E	50	AN	528	E	PKGFTTR
					4180					
										SH.
					343 4Q00877					1
										E



番号 (No.)	部分 (Parts)	材質 (Material)
①	封止樹脂 (Molding compound)	エポキシ樹脂 (Epoxy) 難燃性レベル (UL-Level) UL-94 V0
②	インナーリード処理 (Inner lead finish)	部分銀めっき (Silver spot plating)
③	アウターリード処理 (Outer lead finish)	Sn-Biめっき (Sn-Bi plated) Sn: Tin Bi: Bismuth
④	リード (Lead)	銅合金 (Copper Alloy)
⑤	ボンディングワイヤ (Bonding wire)	金 (Gold)
⑥	チップ (Die)	シリコン (Silicon)
⑦	ダイボンディング材 (Die bonding)	樹脂ペースト (Organic adhesive)

REMARKS		Sn-Biめっき							
DWN.			PROJECTION						DWG.STAMP
CHKD.			SCALE NTS						
APPD.			REGD.	SD	TYPE	D.D	CLASS.	MD	WORK-SPEC No.
Renesas Technology Corp.				E	03	AN	528	E	PKGFTTR
								4182	
								SH.	
				343 4Q01326					1
									E

1234567890 ABCDEFGHIJKLMNOPQRSTUVWXYZ

REVISIONS
P.1 , W#PKGFR,
S#4623

SYM. N.PL 1
5

MチヨウL	D
MQ	1
PROVI. SECT.	co py

A TRAY-DRY-RT01

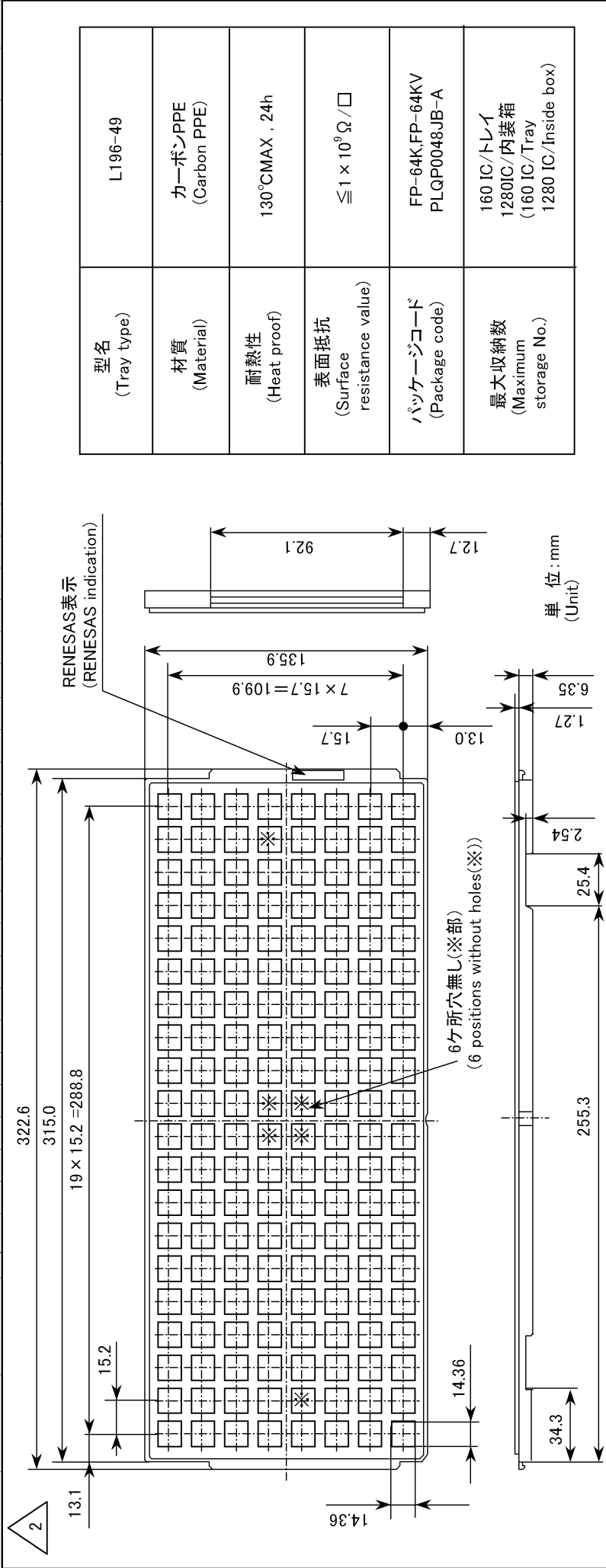
Gr.

1234567890 ABCDEFGHIJKLMNOPQRSTUVWXYZ

SYMBOL			REVISIONS			DATE			REV.D.			CHKD.			APPD.		
2			P.1 , W#PKGFTTR, S#4719														
2																	

Mチケ	D
MQ	1
PROVI.	Co
SECT.	Py

D.CHKD.



型名 (Tray type)	L196-49
材質 (Material)	カーボンPPE (Carbon PPE)
耐熱性 (Heat proof)	130°C MAX , 24h
表面抵抗 (Surface resistance value)	≤ 1 × 10 ⁹ Ω / □
パッケージコード (Package code)	FP-64K,FP-64KV PLQP0048JB-A
最大収納数 (Maximum storage No.)	160 IC / トレイ 1280 IC / 内装箱 (160 IC / Tray 1280 IC / Inside box)

REMARKS				TITLE		DWG. STAMP	
				FTR-TRAY-OUTLN			
				顧客向けトレイ外形図			
				SD TYPE	D.D	CLASS.	MD
				E	03	6G	E
				WORK-SPEC No.		PKGFTTR	
						4719	
				SH.			
				1			
				E			

RENESAS Technology Corp.

343 4Q01665

ICのトレイ収納方向(IC placement direction)

トレイのインデックス
(図中の左下)に対して
ICの1ピンが
同じ方向(左下)に
なる様配列しています。

IC's are placed such
that IC 1st pin
the same direction
to tray index (bottom left).

ICの1ピン表示
(IC index)

トレイインデックス(Tray index)

DWN.

CHKD.

APPD.

REGD.

SCALE
NTS

PROJECTION

TYPE

L196-49

1234567890 ABCDEFGHIJKLMNOPQRSTUVWXYZ